

# OXIDE FILM ON EQUIATOMIC TiNi SHAPE MEMORY ALLOY<sup>①</sup>

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**ABSTRACT** By means of scanning electron microscopy, X-ray diffraction and X-ray photoelectron spectroscopy, the oxide layers on equiatomic TiNi shape memory alloy oxidized in the temperature range from room temperature to 800 °C were studied. The results showed that the thin oxide film naturally formed at room temperature contains Ti element in TiO<sub>2</sub> state and part of Ni element in Ni<sub>2</sub>O<sub>3</sub> state, leaving other Ni still in metallic state; The thin oxide films formed at 300~ 500 °C are characterized by enriched Ti and depleted Ni, both in completely oxidized state. Thick scaling layers were formed above 700 °C, which are proved to be composed of an outer TiO<sub>2</sub> layer dissolved by small amount of Ni and an inner pure Ni<sub>3</sub>Ti layer.

**Key words** TiNi shape memory alloy oxidation surface modification

## 1 INTRODUCTION

Equiatomic TiNi shape memory alloy (SMA) is a novel and promising biomaterial due to its unique and excellent shape memory effect and superelasticity. In addition to the successful application of superelastic TiNi archwire in orthodontics, various medical implants such as blood vessel stent in interventional treatment, which require long term implantation and thus higher biocompatibility, have been proposed and widely studied worldwide. The progress in practical applications of TiNi SMAs has led to extensive researches on relevant properties such as wear resistance and its improvement<sup>[1]</sup> and corrosion resistance<sup>[2]</sup>. It has been demonstrated from the results of corrosion resistance investigation that TiNi SMAs possess poorer pitting resistance than 316L stainless steel in physiological saline solution. As a result, several surface modification methods, including N<sup>+</sup> implantation<sup>[3]</sup>, deposition of plasma polymerized tetrafluoroethylene (PPTFE)<sup>[4]</sup> and chemical passivation in acid solution<sup>[5]</sup>, have so far been studied on the aim to improve its corrosion resistance and biocompatibility. We have shown in previous pa-

pers<sup>[6, 7]</sup> that thermal oxidation can substantially improve the corrosion resistance and biocompatibility of TiNi SMAs. The present research was conducted to clarify the oxidation course and oxide film structure at an extended range of oxidation temperature in an effort to further the understanding of positive effect of oxidation.

## 2 MATERIALS AND EXPERIMENTS

The alloy used in the experiments is a binary TiNi with a chemical composition (in mole fraction) of Ti-50% Ni and a reverse transformation temperature  $A_s$  of about 31 °C. Specimens with a dimension of 15 mm × 15 mm × 0.7 mm were mechanically ground with wet emery paper up to 800 mesh and then polished with diamond paste up to 1 μm before oxidation. The oxidation was conducted inside an electrical furnace in air. A Shimadzu LIBROR L200SM electronic balance was used to measure the weight variation, with an accuracy of 10<sup>-5</sup> g. The scanning electron microscopy (SEM) and energy dispersive X-ray analysis (EDX) were performed on a Hitachi S570 scanning electron microscope. The crystal structure of the scaling layers were analyzed on a

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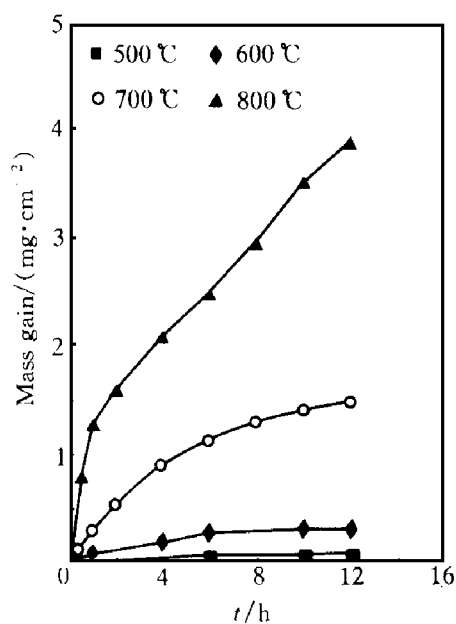
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D/max-B type X-ray diffraction meter using  $\text{CuK}\alpha$  radiation. X-ray Photoelectron Spectroscopy (XPS) was conducted on an ESCAL-ABMK II type X-ray photoelectron spectroscope.

### 3 RESULTS AND DISCUSSION

#### 3.1 Scaling layers formed at high temperature

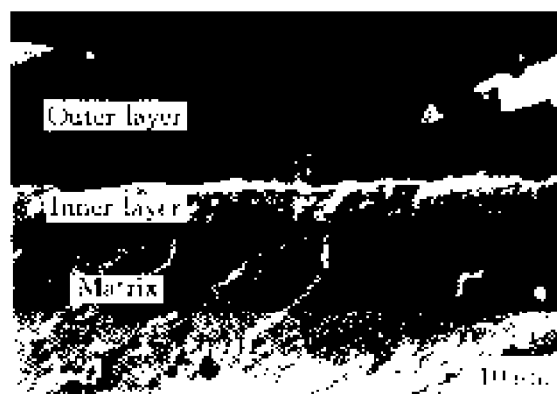
Fig. 1 shows the oxidation kinetic curves at various temperature. It can be seen that the oxidation at 700 and 800 °C may be described by a parabolic rate law, while at 500 and 600 °C the logarithmic rate law may represent the oxidation course. This is in consistence with the results reported in Ref. [8].



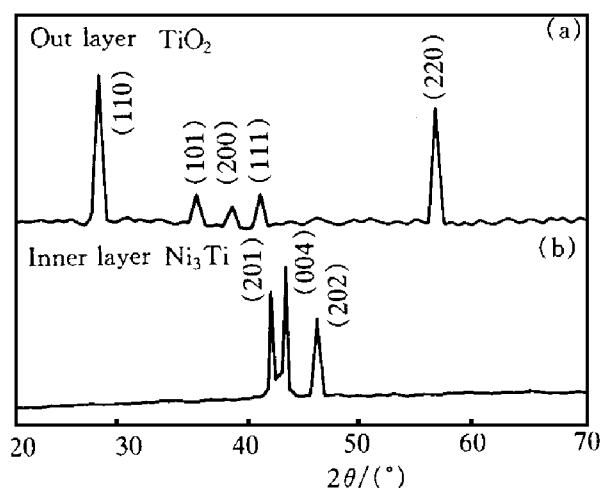
**Fig. 1** The oxidation kinetic curves of TiNi SMA specimens at various oxidation temperatures

The microstructure of the scaling layer on the specimen oxidized at 800 °C for 6 h is shown in Fig. 2. It is clearly seen that the scaling layers are composed of two layers. By means of EDX, the Ti/Ni ratio in the outer and inner layer was determined to be 1: 0.19 and 1: 2.97 (atomic ratio), respectively. And the Ti/Ni ratio in the TiNi matrix was also confirmed concurrently to be 1: 0.98, suggesting that the accuracy is pretty good. In order to identify the crystal structure

of the scaling layers, the X-ray diffraction test was employed and the results are shown in Fig. 3. Fig. 3(a) is the spectrum from the outer layer, which can be identified to be rutile  $\text{TiO}_2$  structure. The experiments revealed that this rutile  $\text{TiO}_2$  layer was loosely attached on the inner layer at room temperature and thus was able to be cleared easily. As a result, the spectrum from the inner layer was obtained and is shown in Fig. 3(b), which can be identified to be the hexagonal  $\text{Ni}_3\text{Ti}$ .



**Fig. 2** The SEM micrograph of scaling layers on TiNi specimen oxidized at 800 °C for 6 h



**Fig. 3** The X-ray diffraction spectra from scaling layers on TiNi specimen oxidized at 800 °C for 6 h

Based on the above results of X-ray diffraction and EDX, it can be concluded that the scaling layers on the specimen oxidized at 800 °C for 6 h are composed of an outer  $\text{TiO}_2$  layer contain-

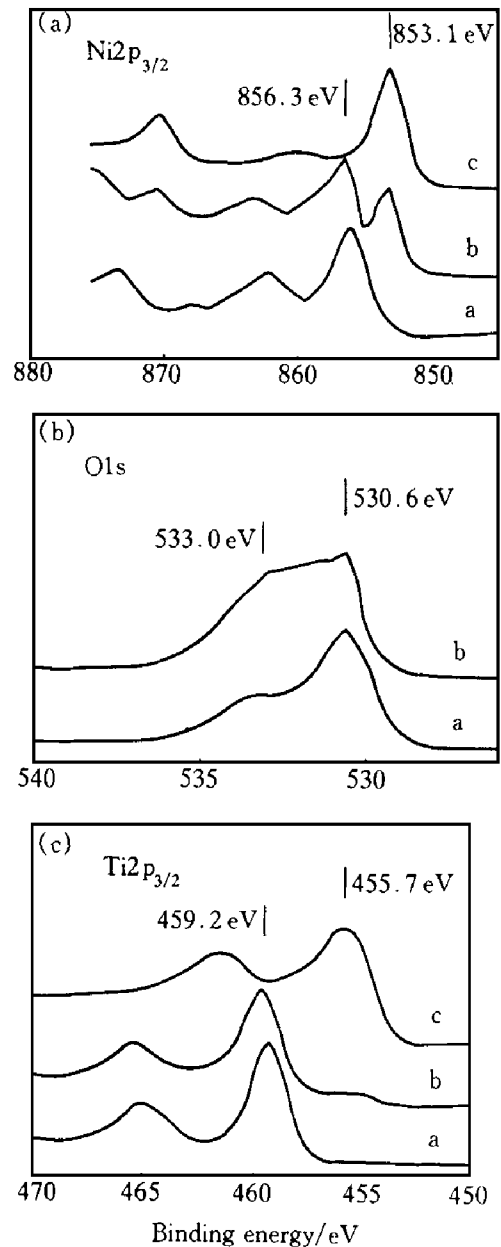
ing small amount of Ni and an inner  $\text{Ni}_3\text{Ti}$  layer. This form of scaling layers is resulted from the selective oxidation of TiNi SMA owing to significant difference in affinity of Ti and Ni element with O element. Selective oxidation makes Ti element preferentially oxidized during oxidation process, which drives the Ni ions to diffuse from oxide film towards interior matrix or/and Ti ions to diffuse in opposite direction. As a result, the outer oxide layer becomes Ti enriched while the region of the matrix close to the oxide layer becomes Ni enriched. As the Ni concentration in this region exceeds the solubility, the Ni riched phase of  $\text{Ni}_3\text{Ti}$ , according to TiNi phase diagram<sup>[8]</sup>, must precipitate and grow.

In practical processing of TiNi SMAs, the oxide layers are frequently washed in mixed solution of  $\text{HNO}_3$ , HF and  $\text{H}_2\text{O}$ . Since the inter-metallic compound  $\text{Ni}_3\text{Ti}$  is considerably more resistant to the attack of HF acid than TiNi matrix, it will be difficult for TiNi SMAs to obtain good surface quality after washing in  $\text{HNO}_3$  and HF acid solution when the  $\text{Ni}_3\text{Ti}$  layer is thick and compact. On the other hand, both  $\text{Ni}_3\text{Ti}$  and TiNi show the metallic lustre and are therefore difficult to distinguish between them. It is extremely important that, for the medical implant made of TiNi SMAs, special care should be taken to assure that  $\text{Ni}_3\text{Ti}$  layer being completely cleared off, in order to avoid the highly cytotoxic  $\text{Ni}_3\text{Ti}$  from contact with living tissue.

### 3.2 Thin oxide films formed at lower temperature

When the oxidation is conducted below  $500^\circ\text{C}$  the oxide film is thinner and is only able to be analyzed by XPS and auger electron spectroscopy. Fig. 4 shows the high resolution XPS spectra of  $\text{Ni}2p$ ,  $\text{Ti}2p$  and  $\text{O}1s$  from three different surface states. For the specimen naturally oxidized at room temperature (curves b), the  $\text{Ni}2p_{3/2}$  spectrum is composed of two peaks with binding energy of 856.3 eV and 853.1 eV, which correspond to  $\text{Ni}_2\text{O}_3$  and metallic Ni respectively. The peaks of 530.6 eV and 533.0 eV in  $\text{O}1s$  spectrum are related to  $\text{TiO}_2$  (or  $\text{Ni}_2\text{O}_3$ ) and  $\text{H}_2\text{O}$  respectively. The  $\text{Ti}2p_{3/2}$  spectrum revealed that

most of the Ti is in  $\text{TiO}_2$  state (binding energy 459.2 eV), with only small quantity existing in metallic state (binding energy 455.7 eV). After oxidation at  $400^\circ\text{C}$  (curves a), it can be seen that the 853.1 eV peak of  $\text{Ni}2p_{3/2}$  and 455.7 eV peak of  $\text{Ti}2p_{3/2}$  from metallic Ni and Ti, respectively, vanish and the 533.0 eV peak of  $\text{O}1s$  from  $\text{H}_2\text{O}$  is considerably reduced. If the naturally oxidized specimen was sputtered by  $\text{Ar}^+$  ion



**Fig. 4** The high resolution XPS spectra of  $\text{Ni}2p$ ,  $\text{O}1s$  and  $\text{Ti}2p$  for TiNi alloy in the surface state

- (a) —Oxidized at  $400^\circ\text{C}$  1 h;
- (b) —Naturally oxidized at room temperature;
- (c) —State (b) plus  $\text{Ar}^+$  ions sputtering for 0.5 h

for 0.5 h, only one peak appears in both  $\text{Ni}2p_{3/2}$  and  $\text{Ti}2p_{3/2}$  spectrum with binding energy of 853.1 eV and 455.7 eV, respectively. This further confirms that the above two peaks are related to the bulk TiNi intermetallic compound. The experiments also revealed that the  $\text{Ni}2p$ ,  $\text{Ti}2p$  and  $\text{O}1s$  spectra from the specimens oxidized at 300 °C and 500 °C for 1 h take the same form as those from the specimen oxidized at 400 °C. Their difference consists in the Ni/Ti ratio which was determined by quantitative XPS analysis, as seen in Table 1. It can be seen that the Ni/Ti ratio is decreased from 0.9:1 to 0.27:1 as oxidation temperature is increased from 300 °C to 500 °C.

**Table 1** The Ni/Ti ratio in oxide film formed at different temperatures for 1 h

Surface state	Ni Ti O atomic ratio
Naturally oxidized in air	1:1
300 °C oxidation	0.9:1:5.5
400 °C oxidation	0.3:1:5
500 °C oxidation	0.27:1:4.5

The above results mean that for TiNi alloy specimens, thermal oxidation between 300~500 °C can effectively modify the existing state of Ni component in the surface oxide film, and furthermore, make Ti component considerably enriched in the surface film, which is apparently due to the selective oxidation of the alloy. Ni is generally considered as a cytotoxic metal element. This Ti-enriched thin surface film can effectively retard the Ni ion release in saline solution and considerably improve the biocompatibility of the TiNi SMAs<sup>[6,7]</sup>. Since the oxide film formed at the temperature range from 300~500 °C is rather thin and thus shape memory effect and shape recovery temperature are seldom influenced by its presence<sup>[9]</sup>, this low tempera-

ture oxidation is really a simple and effective surface modification method for clinical TiNi SMAs with respect to the improvement of biocompatibility.

## 4 CONCLUSION

For equiatomic TiNi SMA, the thin oxide film naturally formed at room temperature consists of completely oxidized Ti element in  $\text{TiO}_2$  state and partially oxidized Ni element in  $\text{Ni}_2\text{O}_3$  state, leaving other Ni in the metallic state; after oxidation at temperature above 700 °C, thicker scaling layers which are composed of an outer  $\text{TiO}_2$  layer dissolved by small amount of Ni and an inner pure  $\text{Ni}_3\text{Ti}$  layer, are formed. The oxidation at temperature between 300~500 °C produces thinner oxide films where Ti is enriched and Ni depleted, both in completely oxidized state.

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